捷多邦,专业PCB打样工厂,24小时加急出货N74F377A OCTAL D-TYPE FLIP-FLOP

SDFS018D - D2932, MARCH 1987 - REVISED OCTOBER 1993

- Contains Eight D-Type Flip-Flops With Single-Rail Outputs
- Clock Enable Latched to Avoid False Clocking
- Applications Include:

 Buffer/Storage Registers
 Shift Registers

 Pattern Generators
- Buffered Common Enable Input
- Package Options Include Plastic Small-Outline Packages and Standard Plastic 300-mil DIPs

DW OR N PACKAGE (TOP VIEW)

CE 1Q	_	U	20	V _{CC}
1D] 8D
	43		18	
2D	4		17	7D
2Q	5		16] 7Q
3Q	6		15] 6Q
3D	[] 7		14] 6D
4D	8 [13] 5D
4Q	9		12] 5Q
GND	10		11	CLK

description

The SN74F377A is a monolithic, positive-edge-triggered, octal, D-type flip-flop with clock enable inputs. The SN74F377A features a latched clock enable ($\overline{\text{CE}}$) input.

Information at the data (D) inputs meeting the setup time requirements is transferred to the Q outputs on the positive-going edge of the clock pulse if \overline{CE} is low. Clock triggering occurs at a particular voltage level and is not directly related to the positive-going pulse. When the clock input is at either the high or low level, the D input signal has no effect at the output. The circuits are designed to prevent false clocking by transitions at the \overline{CE} input.

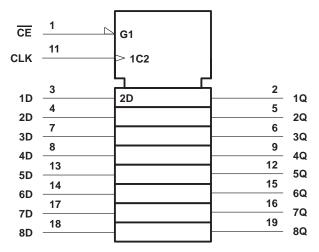
The SN74F377A is characterized for operation from 0°C to 70°C.

FUNCTION TABLE (each flip-flop)

INPUTS			OUTPUT
CE	CLK	D	Q
Н	X	Χ	Q ₀
L	1	Н	Н
L-0	\uparrow	L	L
Х	L	Χ	Q ₀

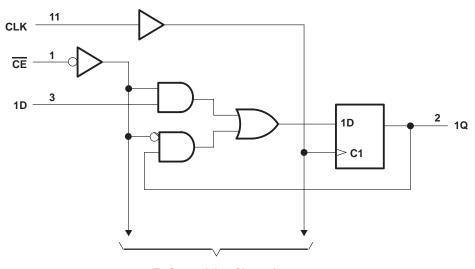
RODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



To Seven Other Channels

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V _{CC}	\dots -0.5 V to 7 V
Input voltage range, V _I (see Note 1)	\dots -1.2 V to 7 V
Input current range	-30 mA to 5 mA
Voltage range applied to any output in the high state	-0.5 V to V_{CC}
Current into any output in the low state	40 mA
Operating free-air temperature range	\dots $$ 0°C to 70°C
Storage temperature range	. -65° C to 150° C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input-voltage ratings may be exceeded provided the input-current ratings are observed.



recommended operating conditions

		MIN	NOM	MAX	UNIT
VCC	Supply voltage	4.5	5	5.5	V
VIH	High-level input voltage	2			V
V _{IL}	Low-level input voltage			0.8	V
lıK	Input clamp current			- 18	mA
ІОН	High-level output current			- 1	mA
loL	Low-level output current			20	mA
T _A	Operating free-air temperature	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		MIN	TYP [†]	MAX	UNIT
VOH	$V_{CC} = 4.5 \text{ V},$	$I_{OH} = -1 \text{ mA}$	2.5	3.4		V
VOH	$V_{CC} = 4.75 \text{ V},$	$I_{OH} = -1 \text{ mA}$	2.7			V
V _{OL}	$V_{CC} = 4.5 \text{ V},$	$I_{OL} = 20 \text{ mA}$		0.3	0.5	V
lį	$V_{CC} = 0$,	V _I = 7 V			0.1	mA
lін	$V_{CC} = 5.5 \text{ V},$	V _I = 2.7 V			20	μΑ
I _{IL}	$V_{CC} = 5.5 \text{ V},$	V _I = 0.5 V			- 0.6	mA
los [‡]	$V_{CC} = 5.5 \text{ V},$	V _O = 0	- 60		- 150	mA
Іссн	$V_{CC} = 5.5 \text{ V},$	See Note 2		55	72	mA
^I CCL	$V_{CC} = 5.5 \text{ V},$	See Note 3		70	90	mA

[†] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

timing requirements

				= 5 V, 25°C	V _{CC} = 4.5 V to 5.5 V, T _A = MIN to MAX§		UNIT
			MIN	MAX	MIN	MAX	
fclock	Clock frequency		0	110	0	110	MHz
t _W	Pulse duration		4		5		ns
	Setup time before CLK↑	Data high or low	2		2		ns
t _{su}		CE high	2.5		2.5		
		CE low	4		4.5		
t _h	11 11 1	Data high or low	1		1		20
	Hold time after CLK↑	CE high or low	0		0		ns

[§] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.



[‡] Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.

NOTES: 2. ICCH is measured after applying a momentary ground, then 4.5 V, to the clock input with all data inputs at 4.5 V and the enable input

^{3.} ICCL is measured after applying a momentary ground, then 4.5 V, to the clock input with all data and enable inputs at GND.

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switching characteristics (see Note 4)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	C _L R _L	$C_L = 50 \text{ pF},$ $R_L = 500 \Omega,$ $T_A = 25^{\circ}C$		V_{CC} = 4.5 V to 5.5 V, C_L = 50 pF, R_L = 500 Ω , T_A = MIN to MAX †		UNIT
fmay			110	125	MAX	MIN 110	IVIAA	MHz
†max			110	120		110		1711 12
t _{PLH}	CLK	Any Q	4	6.5	8.5	4	10	ns
^t PHL		Ally Q	4	7	9	4	10.5	115

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions. NOTE 4: Load circuit and waveforms are shown in Section 1.

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